## Notice of References Cited Application/Control No. 10/761,625 Examiner Tuan H. Nguyen Applicant(s)/Patent Under Reexamination PAN ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*	•	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,255,906	07-2001	Eidson et al.	330/124R
	В	US-7,023,275	04-2006	Miyamoto	330/254
	С	US-5,715,521	02-1998	Fukasawa et al.	455/69
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

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## **NON-PATENT DOCUMENTS**

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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